

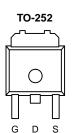
N-Channel 100 V (D-S) MOSFET

PRODUCT SUMMARY						
V _{DS} (V)	$R_{DS(on)}(\Omega)$	I _D (A)	Q _g (Typ.)			
	$0.055 \text{ at V}_{GS} = 10 \text{ V}$	25				
100	0.057 at V _{GS} = 4.5 V	25	21nC			

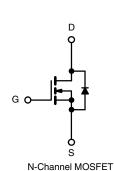
FEATURES

- TrenchFET® power MOSFET
- 100 % UIS tested





Top View



APPLICATIONS

• Primary side switch

PARAMETER		SYMBOL	LIMIT	UNIT
Drain-Source Voltage	V _{DS}	100	V	
Gate-Source Voltage		V _{GS}		± 20
	T _C = 25 °C		25	
Continuous Dusin Comment (T. 175 °C)	T _C = 70 °C		20	
Continuous Drain Current (T _J = 175 °C)	T _A = 25 °C	I _D	12 ^{b, c}	
	T _A = 70 °C		10 ^{b, c}	
Pulsed Drain Current		I _{DM}	75	Α
0 11 0 0 0 1	T _C = 25 °C		50 e	
Continuous Source-Drain Diode Current	T _A = 25 °C	I _S	6.9 b, c	
Avalanche Current Pulse	l 0.1 mll	I _{AS}	33	
Single Pulse Avalanche Energy	L = 0.1 mH	E _{AS}	55	mJ
	T _C = 25 °C		83	
Martin as Barras Blackartina	T _C = 70 °C		58	W
Maximum Power Dissipation	T _A = 25 °C	P _D	8.3 b, c	
	T _A = 70 °C		5.8 b, c	
Operating Junction and Storage Temperature R	T _J , T _{stq}	-55 to +175	°C	

THERMAL RESISTANCE RATINGS						
PARAMETER		SYMBOL	TYPICAL	MAXIMUM	UNIT	
Maximum Junction-to-Ambient b, d	t ≤ 10 s	R _{thJA}	15	18	°C/W	
Maximum Junction-to-Case	Steady State	R_{thJC}	1.5	1.8	C/ VV	

Notes

- a. Based on T_C = 25 °C.
- b. Surface mounted on 1" x 1" FR4 board.
- c. t = 10 s
- d. Maximum under steady state conditions is 50 $^{\circ}\text{C/W}.$
- e. Calculated based on maximum junction temperature. Package limitation current is 50 A.

服务热线:400-655-8788

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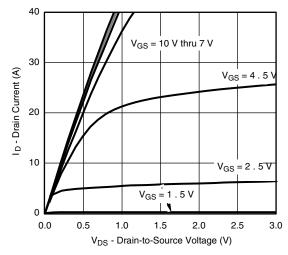
PARAMETER	SYMBOL TEST CONDITIONS		MIN.	TYP.	MAX.	UNIT	
Static							
Drain-Source Breakdown Voltage	V _{DS}	V _{GS} = 0 V, I _D = 250 μA	100	-	-	V	
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	J 050 A	-	165	-	mV/°C	
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	$I_D = 250 \mu\text{A}$	-	-11	-		
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	0.8	1.2	1.6	V	
Gate-Source Leakage	I _{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$	-	-	± 100	nA	
Zero Gate Voltage Drain Current	Inno	V _{DS} = 100 V, V _{GS} = 0 V	-	=	1	1 μA	
Zero date voltage brain ourient	I _{DSS}	$V_{DS} = 100 \text{ V}, V_{GS} = 0 \text{ V}, T_{J} = 55 ^{\circ}\text{C}$	-	-	10	μΑ	
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \ge 5 \text{ V}, V_{GS} = 10 \text{ V}$	25	-	-	Α	
Drain-Source On-State Resistance a	R _{DS(on)}	$V_{GS} = 10 \text{ V}, I_{D=12A}$	-	0.055		Ω	
Drain Godice on Glate Resistance	TIDS(on)	V_{GS} =4.5 V, I_D =8A		0.057			
Forward Transconductance a	g _{fs}	$V_{DS} = 15 \text{ V}, I_{D} = 12 \text{ A}$	-	25	-	S	
Dynamic ^b							
Input Capacitance	C _{iss}		-	1800	-	pF	
Output Capacitance	Coss	$V_{DS} = 12 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$	-	180	-		
Reverse Transfer Capacitance	C _{rss}		-	60	-		
Total Gate Charge	Q_g		-	21	32	nC	
Gate-Source Charge	Q _{gs}	$V_{DS} = 50 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 12 \text{ A}$	-	10	-		
Gate-Drain Charge	Q_{gd}		-	9	-		
Gate Resistance	R_g	f = 1 MHz	-	1.5	-	Ω	
Turn-On Delay Time	t _{d(on)}		-	10	15	- ns	
Rise Time	t _r	$V_{DD} = 50 \text{ V}, R_L = 5 \Omega$	-	10	15		
Turn-Off Delay Time	t _{d(off)}	$I_D \cong 10$ A, $V_{GEN} = 10$ V, $R_g = 1$ Ω	-	15	25		
Fall Time	t _f		-	10	15		
Drain-Source Body Diode Characteristic	s		L	l	L		
Continuous Source-Drain Diode Current	Is	T _C = 25 °C	-	-	50		
Pulse Diode Forward Current ^a	I _{SM}		-	-	40	A	
Body Diode Voltage	V_{SD}	I _S = 10 A	-	0.8	1.2	V	
Body Diode Reverse Recovery Time	t _{rr}		-	50	75	ns	
Body Diode Reverse Recovery Charge	Q _{rr}		-	100	150	nC	
Reverse Recovery Fall Time	t _a	$I_F = 10 \text{ A}, \text{ di/dt} = 100 \text{ A/}\mu\text{s}, T_J = 25 ^{\circ}\text{C}$	-	38	-		
Reverse Recovery Rise Time	t _b	_		12	_	ns	

Note

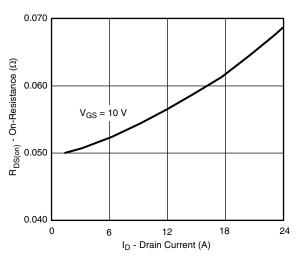
- a. Pulse test; pulse width $\leq 300~\mu s,$ duty cycle $\leq 2~\%.$
- b. Guaranteed by design, not subject to production testing.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

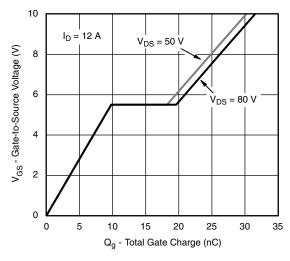




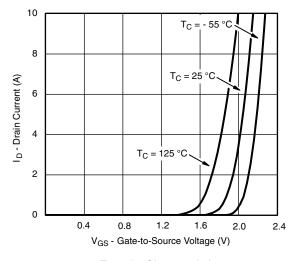
Output Characteristics



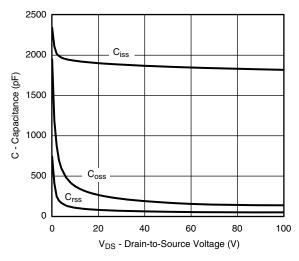
On-Resistance vs. Drain Current



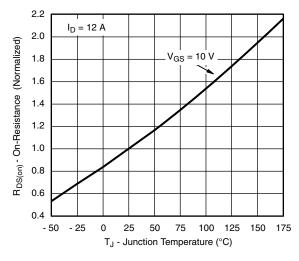
Gate Charge



Transfer Characteristics

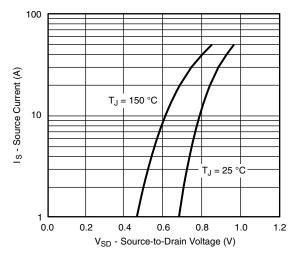


Capacitance

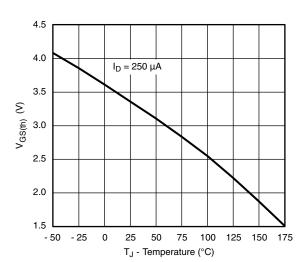


On-Resistance vs. Junction Temperature

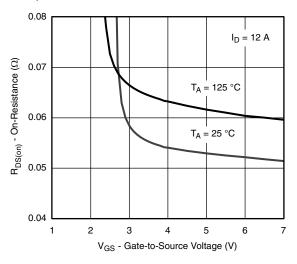




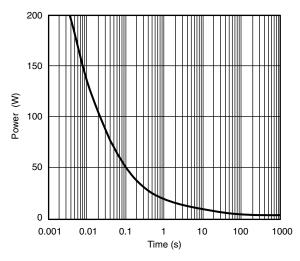
Source-Drain Diode Forward Voltage



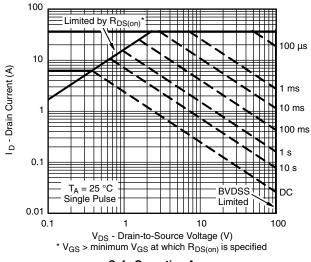
Threshold Voltage



R_{DS(on)} vs. V_{GS} vs. Temperature

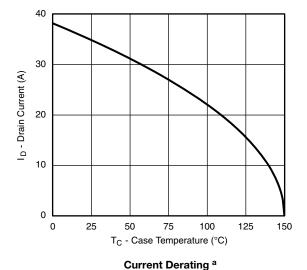


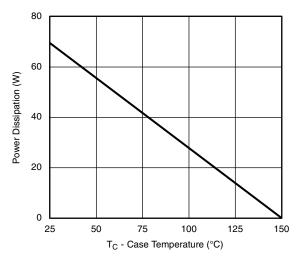
Single Pulse Power, Junction-to-Ambient



Safe Operating Area





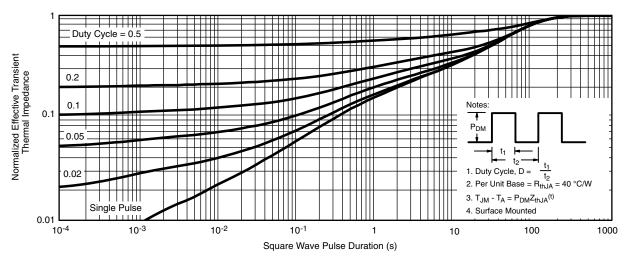


Power Derating

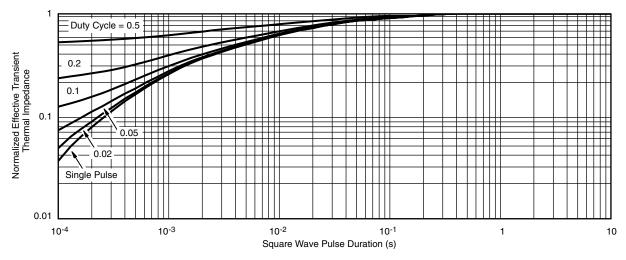
Note

a. The power dissipation P_D is based on T_J (max.) = 150 °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.





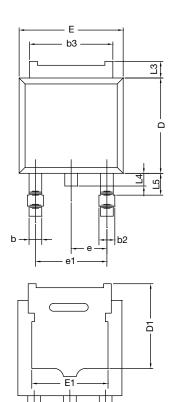
Normalized Thermal Transient Impedance, Junction-to-Ambient

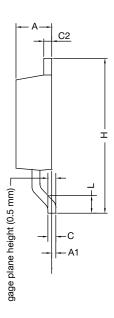


Normalized Thermal Transient Impedance, Junction-to-Case



TO-252AA Case Outline





	MILLIMETERS		INC	HES		
DIM.	MIN.	MAX.	MIN.	MAX.		
А	2.18	2.38	0.086	0.094		
A1	-	0.127	-	0.005		
b	0.64	0.88	0.025	0.035		
b2	0.76	1.14	0.030	0.045		
b3	4.95	5.46	0.195	0.215		
С	0.46	0.61	0.018	0.024		
C2	0.46	0.89	0.018	0.035		
D	5.97	6.22	0.235	0.245		
D1	4.10	-	0.161	-		
Е	6.35	6.73	0.250	0.265		
E1	4.32	-	0.170	-		
Н	9.40	10.41	0.370	0.410		
е	2.28	2.28 BSC		BSC		
e1	4.56 BSC		0.180 BSC			
L	1.40	1.78	0.055	0.070		
L3	0.89	1.27	0.035	0.050		
L4	-	1.02	-	0.040		
L5	1.01	1.52	0.040	0.060		
ECN: T16-0236-Rev. P, 16-May-16						

DWG: 5347

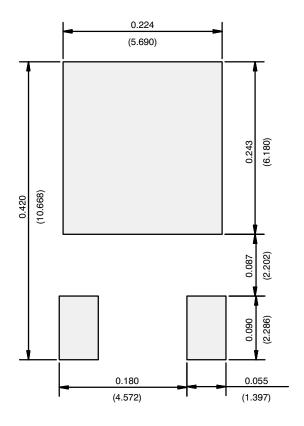
Notes

• Dimension L3 is for reference only.

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RECOMMENDED MINIMUM PADS FOR DPAK (TO-252)



Recommended Minimum Pads Dimensions in Inches/(mm)



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